











#### SN74HCS7002-Q1

ZHCSK73B - AUGUST 2019-REVISED OCTOBER 2019

# 具有施密特触发输入的 SN74HCS7002-Q1 汽车类四路双输入或非门

## 1 特性

- 符合面向汽车 应用的 AEC-Q100 标准:
  - 器件温度等级 1: -40°C 至 +125°C, T<sub>A</sub>
  - 器件 HBM ESD 分类等级 2
  - 器件 CDM ESD 分类等级 C6
- 宽工作电压范围: 2V 至 6V
- 施密特触发输入可实现慢速或高噪声输入信号
- 低功耗
  - I<sub>CC</sub> 典型值为 100nA
  - 输入泄漏电流典型值为 ±100nA
- 电压为 5V 时,输出驱动为 ±7.8mA

## 2 应用

- 警报/篡改检测电路
- S-R 锁存

## 3 说明

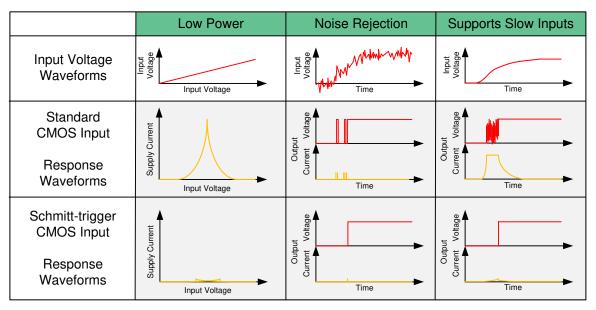
此器件包含四个具有施密特触发输入的独立双输入或非门。每个逻辑门以正逻辑执行布尔函数  $Y = \overline{A + B}$ 。

## 器件信息<sup>(1)</sup>

器件型号	封装	封装尺寸 (标称值)		
SN74HCS7002QDRQ 1	SOIC (14)	8.70mm × 3.90mm		
SN74HCS7002QPWR Q1	TSSOP (14)	5.00mm × 4.40mm		

(1) 如需了解所有可用封装,请参阅数据表末尾的可订购产品附录。

## 施密特触发输入的优势





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# 4 修订历史记录

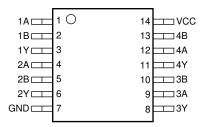
注: 之前版本的页码可能与当前版本有所不同。

Changes from Revision A (September 2019) to Revision B	Page
• 已添加 向数据表添加了 D 封装	1
Changes from Original (August 2019) to Revision A	Page
Changed the recommended ambient temp from -55 to 125 C to -40 to 125 C	4



# 5 Pin Configuration and Functions

## D or PW Package 14-Pin SOIC or TSSOP Top View



## **Pin Functions**

	PIN	I/O	DESCRIPTION					
NAME	NO.	1/0	DESCRIFTION					
1A	1	Input	Channel 1, Input A					
1B	2	Input	Channel 1, Input B					
1Y	3	Output	Channel 1, Output Y					
2A	4	Input	Channel 2, Input A					
2B	5	Input	Channel 2, Input B					
2Y	6	Output	Channel 2, Output Y					
GND	7	_	Ground					
3Y	8	Output	Channel 3, Output Y					
3A	9	Input	Channel 3, Input A					
3B	10	Input	Channel 3, Input B					
4Y	11	Output	Channel 4, Output Y					
4A	12	Input	Channel 4, Input A					
4B	13	Input	Channel 4, Input B					
V <sub>CC</sub>	14		Positive Supply					



## 6 Specifications

## 6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_{I} < -0.5 \text{ or } V_{I} > V_{CC} + 0.5$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_{O} < -0.5 \text{ or } V_{O} > V_{CC} + 0.5$		±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$		±35	mA
	Continuous current through V <sub>CC</sub> or GND			±50	mA
T <sub>J</sub>	Junction temperature (3)		150	°C	
T <sub>stg</sub>	Storage temperature	<b>–</b> 65	150	°C	

<sup>(1)</sup> Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub> Electrostatic discharge	Human body model (HBM), per AEC Q100-002 <sup>(1)</sup> HBM ESD Classification Level 2	±4000	W	
		Charged device model (CDM), per AEC Q100- 011 CDM ESD Classification Level C6	±1500	V

<sup>(1)</sup> AEC Q100-002 indicate that HBM stressing shall be in accordrance with the ANSI/ESDA/JEDEC JS-001 specification.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{CC}$	Supply voltage	2	6	V
VI	Input voltage	0	$V_{CC}$	V
Vo	Output voltage	0	Vcc	V
Δt/Δν	Input transition rise and fall rate		Unlimited	ns/V
T <sub>A</sub>	Ambient temperature	-40	125	°C

### 6.4 Thermal Information

		SN74HCS		
	THERMAL METRIC	PW (TSSOP)	D (SOIC)	UNIT
		14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	151.7	133.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	79.4	89.0	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	94.7	89.5	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	25.2	45.5	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	94.1	89.1	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

<sup>(2)</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed. Do not exceed the absolute maximum voltage supply rating.

<sup>(3)</sup> Guaranteed by design.



## 6.5 Electrical Characteristics

over operating free-air temperature range; typical ratings measured at  $T_A = 25$ °C (unless otherwise noted).

	PARAMETER	TEST CO	TEST CONDITIONS		MIN	TYP	MAX	UNIT		
				2 V	0.7		1.5			
$V_{T+}$	Positive switching threshold			4.5 V	1.7		3.15	V		
				6 V	2.1		4.2			
				2 V	0.3		1.0			
$V_{T-}$	Negative switching threshold			4.5 V	0.9		2.2	V		
				6 V	1.2		3.0			
				2 V	0.2		1.0			
$\Delta V_{T}$	Hysteresis (V <sub>T+</sub> - V <sub>T-</sub> )			4.5 V	0.4		1.4	V		
				6 V	0.6		1.6			
					$I_{OH} = -20 \mu A$	2 V to 6 V	$V_{CC} - 0.1$	$V_{CC} - 0.002$		
$V_{OH}$	High-level output voltage	$V_I = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -6 \text{ mA}$	4.5 V	4.0	1.3		V		
			$I_{OH}$ = -7.8 mA	6 V	5.4	5.75				
			$I_{OL} = 20 \mu A$	2 V to 6 V		0.002	0.1			
$V_{OL}$	Low-level output voltage	$V_I = V_{IH}$ or $V_{IL}$	$I_{OL} = 6 \text{ mA}$	4.5 V		0.18	0.30	V		
			$I_{OL} = 7.8 \text{ mA}$	6 V		0.22	0.33			
I	Input leakage current	$V_I = V_{CC}$ or 0		6 V		±100	±1000	nA		
I <sub>CC</sub>	Supply current	$V_I = V_{CC}$ or 0, $I_C$	0 = 0	6 V		0.1	2	μΑ		
Ci	Input capacitance			2 V to 6 V			5	pF		
C <sub>pd</sub>	Power dissipation capacitance per gate	No load		2 V to 6 V		10		pF		

## 6.6 Switching Characteristics

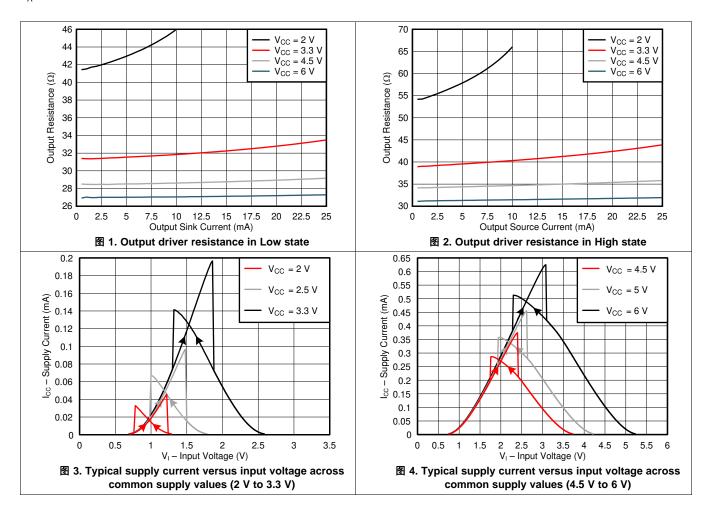
over operating free-air temperature range; typical ratings measured at  $T_A = 25$ °C (unless otherwise noted). See Parameter Measurement Information.

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
	t <sub>pd</sub> Propagation delay			2 V		16	32	
t <sub>pd</sub>		A or B	Υ	4.5 V		7	15	ns
				6 V		6	12	
	Transition-time	A or B	Υ	2 V		7.7	13	
t <sub>t</sub>				4.5 V		4	6.1	ns
				6 V		3.5	5.1	



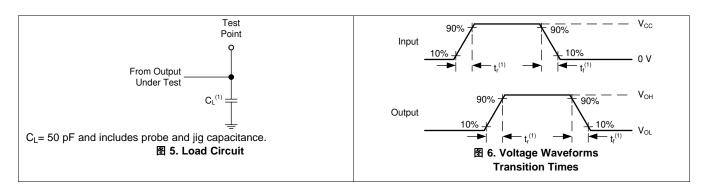
## 6.7 Typical Characteristics

 $T_A = 25^{\circ}C$ 



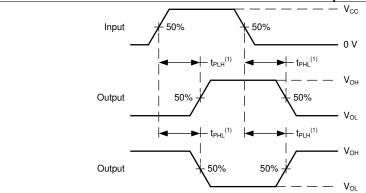
## 7 Parameter Measurement Information

- Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_t < 2.5 \text{ ns}$ .
- The outputs are measured one at a time, with one input transition per measurement.





# Parameter Measurement Information (接下页)



The maximum between  $t_{\text{PLH}}$  and  $T_{\text{PHL}}$  is used for  $t_{\text{pd}}.$ 

图 7. Voltage Waveforms Propagation Delays

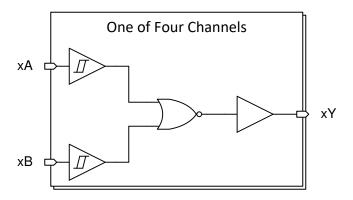


## 8 Detailed Description

#### 8.1 Overview

This device contains four independent 2-input NOR Gates with Schmitt-trigger inputs. Each gate performs the Boolean function  $Y = \overline{A + B}$  in positive logic.

### 8.2 Functional Block Diagram



#### 8.3 Feature Description

#### 8.3.1 Balanced CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

#### 8.3.2 CMOS Schmitt-Trigger Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using ohm's law  $(R = V \div I)$ .

The Schmitt-trigger input architecture provides hysteresis as defined by  $\Delta V_T$  in the *Electrical Characteristics*, which makes this device extremely tolerant to slow or noisy inputs. While the inputs can be driven much slower than standard CMOS inputs, it is still recommended to properly terminate unused inputs. Driving the inputs slowly will also increase dynamic current consumption of the device. For additional information regarding Schmitt-trigger inputs, please see Understanding Schmitt Triggers.

#### 8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in № 8.

#### **CAUTION**

Voltages beyond the values specified in the Absolute Maximum Ratings table can cause damage to the device. The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



# Feature Description (接下页)

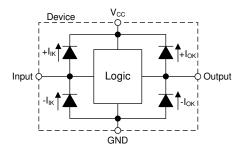


图 8. Electrical Placement of Clamping Diodes for Each Input and Output

## 8.4 Device Functional Modes

表 1. Function Table

INP	UTS	OUTPUT
Α	В	Y
L	L	Н
Н	X	L
Х	Н	L



## 9 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 9.1 Application Information

In this application, two 2-input NOR gates are used to create an SR latch as shown in 🛚 9. The two additional gates can be used for a second SR latch, or the inputs can be grounded and both channels left unused.

The SN74HCS7002-Q1 is used to drive the tamper indicator LED and provide one bit of data to the system controller. When the tamper switch outputs HIGH, the output Q becomes HIGH. This output remains HIGH until the system controller addresses the event and sends a HIGH signal to the R input which returns the Q output back to LOW.

The user can add a small RC to the feedback path of the NOR gates to default the output to a certain state, which can create slow transition rates. This fact makes the SN74HCS7002-Q1 ideal for the application because it has Schmitt-trigger inputs that do not have input transition rate requirements.

## 9.2 Typical Application

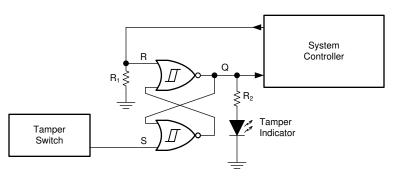


图 9. Typical application block diagram

#### 9.2.1 Design Requirements

- All signals in the system operate at 5 V
- Avoid unstable state by not having HIGH signals on both inputs
- Q output is HIGH when S is HIGH
  - Q output remains High until R is HIGH

#### 9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics*.

The supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74HCS7002-Q1 plus the maximum supply current,  $I_{CC}$ , listed in the *Electrical Characteristics*. The logic device can only source or sink as much current as it is provided at the supply and ground pins, respectively. Be sure not to exceed the maximum total current through GND or  $V_{CC}$  listed in the *Absolute Maximum Ratings*.

The SN74HCS7002-Q1 can drive a load with a total capacitance less than or equal to 50 pF connected to a high-impedance CMOS input while still meeting all of the datasheet specifications. Larger capacitive loads can be applied, however it is not recommended to exceed 70 pF.

Total power consumption can be calculated using the information provided in CMOS Power Consumption and  $C_{pd}$  Calculation.



## Typical Application (接下页)

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.

#### **CAUTION**

The maximum junction temperature,  $T_J(max)$  listed in the *Absolute Maximum Ratings*, is an *additional limitation* to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

## 9.2.1.2 Input Considerations

Input signals must cross  $V_{t-}(min)$  to be considered a logic LOW, and  $V_{t+}(max)$  to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either  $V_{CC}$  or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the SN74HCS7002-Q1, as specified in the *Electrical Characteristics*, and the desired input transition rate. A 10-k $\Omega$  resistor value is often used due to these factors.

The SN74HCS7002-Q1 has no input signal transition rate requirements because it has Schmitt-trigger inputs.

Another benefit to having Schmitt-trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the  $\Delta V_T$ (min) in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than  $V_{CC}$  or ground is plotted in the *Typical Characteristics*.

Refer to the *Feature Description* for additional information regarding the inputs for this device.

#### 9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Electrical Characteristics*. Similarly, the ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OL}$  specification in the *Electrical Characteristics*. The plots in and provide a typical relationship between output voltage and current for this device.

Unused outputs can be left floating.

Refer to Feature Description for additional information regarding the outputs for this device.

#### 9.2.2 Detailed Design Procedure

- 1. Add a decoupling capacitor from  $V_{CC}$  to GND. The capacitor needs to be placed physically close to the device and electrically close to both the  $V_{CC}$  and GND pins. An example layout is shown in the *Layout*.
- 2. Ensure the capacitive load at the output is ≤ 70 pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74HCS7002-Q1 to the receiving device.
- 3. Ensure the resistive load at the output is larger than  $(V_{CC} / 25 \text{ mA}) \Omega$ . This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
- Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation



# Typical Application (接下页)

# 9.2.3 Application Curves

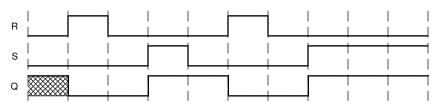


图 10. Application timing diagram



## 10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in 81.

## 11 Layout

#### 11.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or VCC, whichever makes more sense for the logic function or is more convenient.

## 11.2 Layout Example

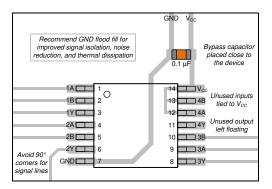


图 11. Example layout for the SN74HCS7002-Q1



## 12 器件和文档支持

## 12.1 文档支持

#### 12.1.1 相关文档

请参阅如下相关文档:

- 《HCMOS 设计注意事项》
- 《CMOS 功耗与 CPD 计算》
- 《使用逻辑器件进行设计》

## 12.2 相关链接

下表列出了快速访问链接。类别包括技术文档、支持与社区资源、工具和软件,以及申请样片或购买产品的快速链接。

### 12.3 社区资源

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 12.4 商标

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

#### 12.5 静电放电警告



这些装置包含有限的内置 ESD 保护。 存储或装卸时,应将导线一起截短或将装置放置于导电泡棉中,以防止 MOS 门极遭受静电损伤。

### 12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且不会对此文档进行修订。如需获取此数据表的浏览器版本,请查阅左侧的导航栏。

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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
	(.,	(=)			(0)	(4)	(5)		(6)
SN74HCS7002QDRQ1	Active	Production	SOIC (D)   14	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC7002Q
SN74HCS7002QDRQ1.A	Active	Production	SOIC (D)   14	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC7002Q
SN74HCS7002QPWRQ1	Active	Production	TSSOP (PW)   14	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC7002Q
SN74HCS7002QPWRQ1.A	Active	Production	TSSOP (PW)   14	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC7002Q

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN74HCS7002-Q1:

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# **PACKAGE OPTION ADDENDUM**

www.ti.com 23-May-2025

● Catalog : SN74HCS7002

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product



SMALL OUTLINE INTEGRATED CIRCUIT



#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



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  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



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